

## Description

The FDS4435A uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

### **General Features**

V<sub>DS</sub> =-30 V I<sub>D</sub> = -11A

 $R_{DS(ON)}$  < 16m $\Omega$  @ V<sub>GS</sub>=10V

# Application

Battery protection

Load switch

Uninterruptible power supply

#### Package Marking and Ordering Information

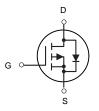
Product ID	Pack	Marking	Qty(PCS)
FDS4435A	SOP-8	4435 XXX YYY	3000

### Absolute Maximum Ratings (Tc=25°C unless otherwise noted )

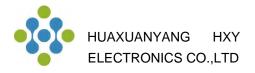
Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain-Source Voltage	- 30	V
VGS	Gate-Source Voltage	±20	V
ID@TA=25°C	Drain Current <sup>3</sup> , V <sub>GS</sub> @ 10V	-11	А
IDM	Pulsed Drain Current <sup>1</sup>	-40	А
P₀@T <sub>A</sub> =25°C	Total Power Dissipation	3.7	W
TSTG	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
Rthj-a	Maximum Thermal Resistance, Junction-ambient <sup>3</sup>	33.8	°C/W



SOP-8



P-Channel MOSFET



# **Electrical Characteristics (T**J = 25°C, unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units	
Off Charac	cteristic	I		1			
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> = -250µA	-30	-	-	V	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -30V, V <sub>GS</sub> =0V,	-	-	-1	μA	
I <sub>GSS</sub>	Gate to Body Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> = ±20V	-	-	±100	nA	
On Charac	teristics						
$V_{GS(th)}$	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> = -250µA	-1.0	-1.6	-2.5	V	
	Static Drain-Source on-Resistance	V <sub>GS</sub> = -10V, I <sub>D</sub> = -10A	_	13	16	mΩ	
$R_{DS(on)}$		$V_{GS}$ = -4.5V, $I_D$ = -5A	-	18	27		
Dynamic (	Characteristics						
Ciss	Input Capacitance		-	1330	-	pF	
Coss	Output Capacitance	V <sub>DS</sub> = -15V, V <sub>GS</sub> =0V, f=1.0MHz	-	183	-	pF	
Crss	Reverse Transfer Capacitance		-	156	-	pF	
$Q_{g}$	Total Gate Charge		-	22	-	nC	
$Q_gs$	Gate-Source Charge	V <sub>DS</sub> = -15V, I <sub>D</sub> = -5A, V <sub>GS</sub> = -10V	-	1.0	-	nC	
$Q_gd$	Gate-Drain("Miller") Charge	VGS- 10V	-	1.8	-	nC	
Switching	Characteristics						
t <sub>d(on)</sub>	Turn-on Delay Time		-	9	-	ns	
tr	Turn-on Rise Time	V <sub>DD</sub> = -15V, I <sub>D</sub> = -10A,	-	13	-	ns	
t <sub>d(off)</sub>	Turn-off Delay Time	V <sub>GS</sub> =-10V, R <sub>GEN</sub> =2.5Ω	-	48	-	ns	
t <sub>f</sub>	Turn-off Fall Time		-	20	-	ns	
Drain-Sou	rce Diode Characteristics and Maxim	um Ratings					
ls	Maximum Continuous Drain to Source Diode Forward Current		-	-	-11	А	
I <sub>SM</sub>	Maximum Pulsed Drain to Source Did	aximum Pulsed Drain to Source Diode Forward Current		-	-40	Α	
$V_{\text{SD}}$	Drain to Source Diode Forward Voltage	V <sub>GS</sub> =0V, I <sub>S</sub> = -15A	_	-0.8	-1.2	V	
trr	Reverse Recovery Time	<b>T</b> J <b>=25</b> ℃,	-	64	-	ns	
Qrr	Reverse Recovery Charge	V <sub>DD</sub> = -24V,I <sub>F</sub> =-2.8A, dI/dt=-100A/µs	-	25	-	nC	

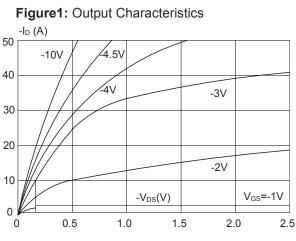
Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

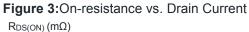
2. EAS condition: T\_J=25  $^\circ \!\! \mathbb{C}$  , V\_Gs=10V, R\_G=25\Omega, L=0.5mH, I\_{AS}=-12.7A

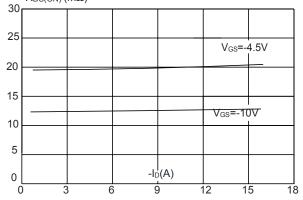
3. Pulse Test: Pulse Width≤300µs, Duty Cycle≤0.5%

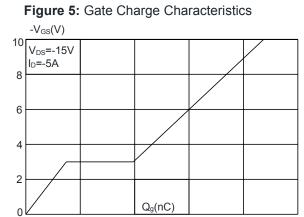


# **Typical Characteristics**







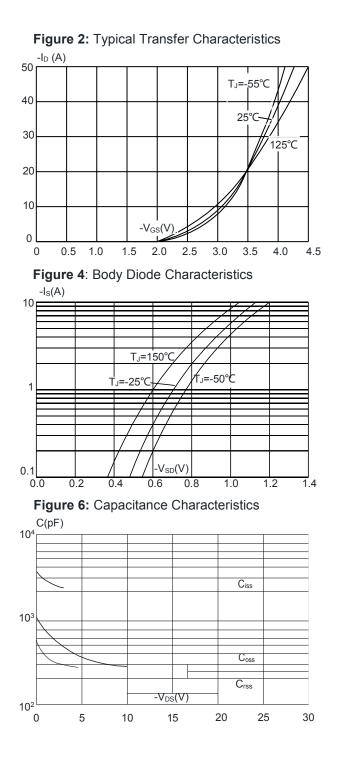


10

15

20

25

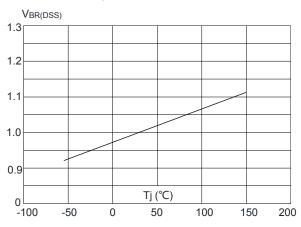


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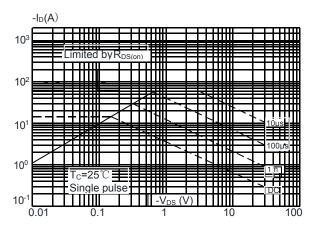
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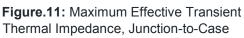


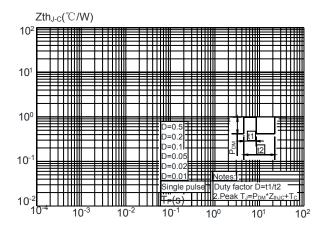
**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature











**Figure 8:** Normalized on Resistance vs. Junction Temperature

P-Channel Enhancement Mode MOSFET

FDS4435A

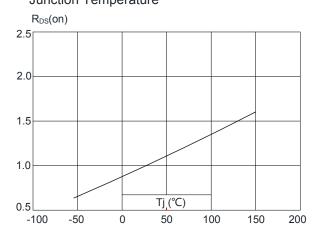
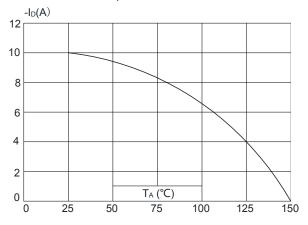
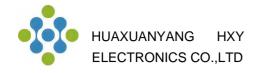
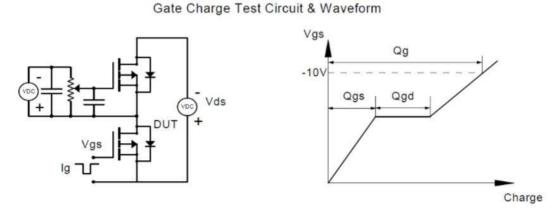


Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature

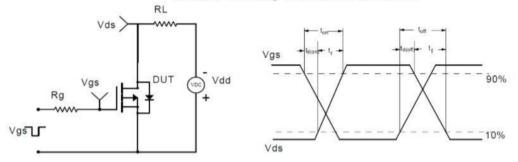




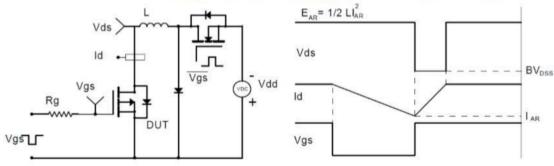
# **Test Circuit**



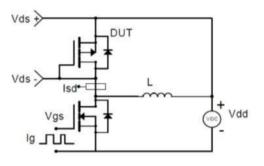
Resistive Switching Test Circuit & Waveforms

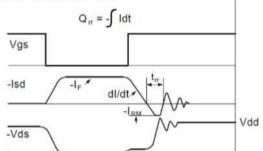


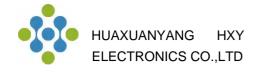
### Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



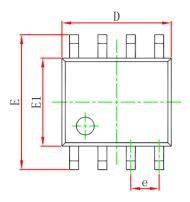
#### Diode Recovery Test Circuit & Waveforms

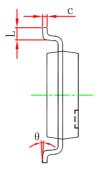


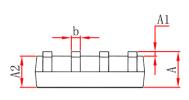




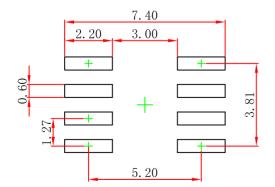
# SOP-8 Package Outline Dimensions







Symbol	Dimensions In Millimeters		Dimensions In Inches		
	Min	Max	Min	Max	
А	1.350	1.750	0.053	0.069	
A1	0.100	0.250	0.004	0.010	
A2	1.350	1.550	0.053	0.061	
b	0.330	0.510	0.013	0.020	
с	0.170	0.250	0.007	0.010	
D	4.800	5.000	0.189	0.197	
e	1.270 (BSC)		0.050 (BSC)		
E	5.800	6.200	0.228	0.244	
E1	3.800	4.000	0.150	0.157	
L	0.400	1.270	0.016	0.050	
θ	0 °	8°	0 °	8°	



Note: 1.Controlling dimension: in millimeters.

2.General tolerance:± 0.05mm.
 3.The pad layout is for reference purposes only.



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